

2nd ANNOUNCEMENT AND CALL FOR PAPERS

The Conference

You are cordially invited to participate in and contribute to the most advanced conferences in pressure and vacuum metrology.

The **CCM International Conference on Pressure and Vacuum Metrology** is the world's leading conference on Measurement-related issues in the pressure and vacuum fields. The conference will review research and developing work on the highest quality primary standards and on the dissemination of traceability to the most exacting and demanding users in the range from 10^{-9} Pa to 10^9 Pa.

This is the 6th conference in a series that began in 1988. Since 1993, it has been held every 6 years and was extended to include the vacuum metrology field in 1999. The conference is organized by the Working Group for Pressure and Vacuum (WG PV) within the Committee for Mass and Related Quantities (CCM), as one of the advisory committees of the meter convention.

The **IMEKO TC16 International Conference** on Pressure and Vacuum Measurement focuses on the practical aspects of pressure and vacuum measurement mainly for industrial sectors like processing and semiconductor industry, photovoltaics, coating, metallurgy, packaging, pharmaceuticals among others, as well for research applications.

The conference is organized by the Technical Committee 16 for Pressure and Vacuum Measurement of the International Measurement Confederation IMEKO and has been held in 2001, 2003, 2007, and 2011.

English will be the language of the conferences.

Scope

6th CCM International Conference on Pressure and Vacuum Metrology

- Primary standards for low, medium and high pressure (including dynamic pressure).
- Primary standards and traceability for partial pressures and leak rates.
- Physical and material properties and phenomena relevant to vacuum and pressure metrology.
- Secondary and transfer standards and innovative and advanced sensors and gauges.
- Secondary and transfer standards for low gas flows (leak rates).
- New approaches to accurate total and partial pressure measurement (e.g. optical methods).
- Comparisons of vacuum and pressure standards and very low gas flows (leak rates) at the international level (registered by the BIPM).
- Traceability, dissemination, calibration and accreditation of vacuum and pressure measurements.
- Challenging applications for most accurate pressure and vacuum measurements.

5th IMEKO TC16 International Conference

- National secondary standards for low, medium and high pressure (including dynamic pressure).
- Provision of measurement standards in newly developing economies.
- Comparisons of vacuum and pressure standards and very low gas flows (leak rates) at the national or international level (not registered by the BIPM).
- Pressure and vacuum sensors for industry.
- Partial pressure measurement.
- Standardization of pressure and vacuum technology.
- New approaches, techniques and instrumentation for accurate pressure calibration.
- Challenges of pressure and vacuum measurement for research and industrial applications.

Deadlines

December 15, 2016

Early submission deadline for abstracts

January 20, 2017

Notification of acceptance of abstracts submitted by December 15, 2016

January 31, 2017

Final deadline for submission of abstracts

January 31, 2017

Reduced rate deadline

February 24, 2017

Notification of acceptance of abstracts submitted after December 15, 2016

May 5, 2017

Submission of papers for proceedings

May 7, 2017

Welcome reception

May 8 - 10, 2017

Academic sessions and exhibition

Invited Speakers

Jay Hendricks, Thermodynamic Metrology Group Leader, NIST, United States. *New Pressure Standard by Refractive Index Measurement.*

Karl Jousten, CCM WG PV Chair, Head of Vacuum Metrology Group, PTB, Germany. *Traceable Partial Pressure and Outgassing Rate Measurements.*

Jim Fedchak, Thermodynamic Metrology Group, NIST, United States. *Development of a New UHV Pressure Standard (Cold Atom Trap Vacuum Standard).*

Wladimir Sabuga, Head of Pressure Working Group, PTB, Germany. *High Pressure Metrology for Industrial Applications.*

Kevin Douglass, Thermodynamic Metrology Group, NIST, United States. *Traceable Dynamic Measurement of Mechanical Quantities.*

Michael Krystek, Member of the Consultative Committee for Units -CCU, PTB, Germany. *Redefinition of the Kilogram and the New SI.*

Jorge Torres, CCM WG PV Vice-Chair, Head of Force and Pressure Metrology Group, CENAM, Mexico. *How to Systematically Build up Calibration Capabilities for Pressure and Vacuum in a Less- Developed Country.*

Chandra Romel, Laser Interferometer Gravitational-Wave Observatory LIGO, United States. *Incidence of Ultra High Vacuum Technology in the Measurement of Gravitational Waves.*

Janez Setina, Head of Pressure Metrology, IMT, Slovenia. *Economical Multi-Purpose Vacuum Calibration System for Smaller Metrological Institutes.*

Submission of abstracts

Abstracts should not exceed 250-300 words in length. Figures and diagrams are not permitted. The program committee will take into account your preference for giving either a poster or an oral presentation, but cannot guarantee that your preferred option for presenting will be accepted, due to logistics limitations. You will be notified of the presentation format in advance. You will be asked to submit on one of the categories listed in "Scope."

Proceedings

Papers submitted by the beginning of the conference will be reviewed by the Scientific Committee. Reviewed and accepted papers will be published in the journals: *Metrologia*, *Measurement*, *Acta IMEKO* and *e-medida*.

**We look forward to meeting you
in Pereira in 2017!**

Karl Jousten, CCM WG PV Chair
Jorge Torres, CCM WG PV Vice-Chair
Tokihiko Kobata, IMEKO TC 16 Chair
Sam-Yong Woo, IMEKO TC 16 Former Chair

Registration & Payment

Registration fees*

CATEGORY	Early By Jan 31, 2017	Normal By Apr 30, 2017	Late After Apr 30, 2017
General	USD \$600.00	USD \$650.00	USD \$700.00
Student**	USD \$360.00	USD \$390.00	USD \$420.00
Companion, Spouse	USD \$200.00	USD \$200.00	USD \$220.00

*The registration fee is NON-REFUNDABLE.

**BSc-, MSc and Diploma-students, no PhD-students. Valid student ID must be presented at conference or payment will be required.

The fee Includes

General

- Welcome reception
- Access to all academic sessions
- Admission to a commercial product and services exhibition
- Lunches (for all 3 conference days)
- Coffee breaks (for all 3 conference days)
- Conference dinner on Tuesday night (May 9)
- Conference tote

Student

- Access to all academic sessions
- Admission to a commercial product and services exhibition
- Lunches (for all 3 conference days)
- Coffee breaks (for all 3 conference days)
- Conference tote

Accompanying person

- Welcome reception
- Lunches (for all 3 conference days)
- Conference dinner on Tuesday night (May 9)

Method of payment

You can pay online with our fully secured e-commerce payment system, PayPal.

http://ccmpv6.inm.gov.co/index.php?option=com_content&view=article&id=37&lang=es

Once payment has been received, we will confirm your registration.



For more information:

<http://ccmpv6.inm.gov.co/> ccm-imeko@inm.gov.co